

# 4-Mbit (512K x 8) Static RAM

#### **Features**

- Temperature Ranges
  - Commercial: 0°C to 70°C
     Industrial: -40°C to 85°C
     Automotive: -40°C to 125°C
- · High speed
  - t<sub>AA</sub> = 10 ns
- · Low active power
  - 324 mW (max.)
- 2.0V data retention
- Automatic power-down when deselected
- . TTL-compatible inputs and outputs
- Easy memory expansion with CE and OE features

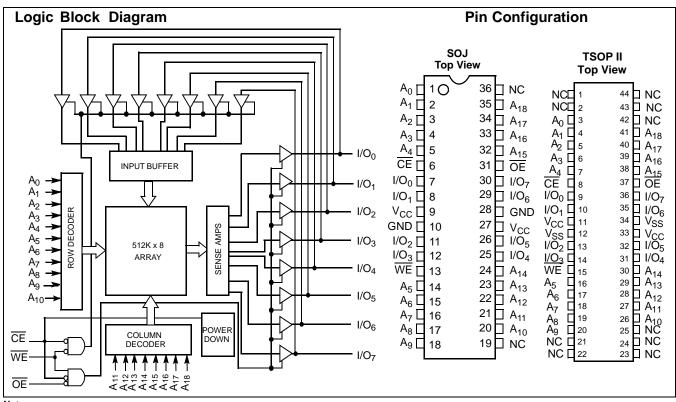
### Functional Description[1]

The CY7C1049CV33 is a high-performance CMOS Static RAM organized as 524,288 words by 8 bits. Easy memory expansion is provided by an active LOW Chip Enable ( $\overline{CE}$ ), an active LOW Output Enable ( $\overline{OE}$ ), and three-state drivers. Writing to the device is accomplished by taking Chip Enable ( $\overline{CE}$ ) and Write Enable ( $\overline{WE}$ ) inputs LOW. Data on the eight I/O pins (I/O<sub>0</sub> through I/O<sub>7</sub>) is then written into the location specified on the address pins ( $A_0$  through  $A_{18}$ ).

Reading from the device is accomplished by taking Chip Enable (<u>CE</u>) and Output Enable (<u>OE</u>) LOW while forcing Write Enable (WE) HIGH. Under these conditions, the contents of the memory location specified by the address pins will appear on the I/O pins.

The eight input/output pins (I/O $_0$  through I/O $_7$ ) are placed in a high-impedance state when the device is deselected (CE HIGH), the outputs are disabled (OE HIGH), or during a Write operation (CE LOW, and WE LOW).

The CY7C1049CV33 is available in standard 400-mil-wide 36-pin SOJ package and 44-pin TSOP II package with center power and ground (revolutionary) pinout.



Notes:

<sup>1.</sup> For guidelines on SRAM system design, please refer to the System Design Guidelines Cypress application note, available on the internet at www.cypress.com.



## **Selection Guide**

		-8	-10	-12	-15	-20	Unit
Maximum Access Time		8	10	12	15	20	ns
Maximum Operating Current	Commercial	100	90	85	80	80	mA
	Industrial	110	100	95	90	90	mA
	Automotive	-	-	-	95	-	mA
Maximum CMOS Standby Current	Commercial / Industrial	10	10	10	10	10	mA
	Automotive	-	-	-	15	-	mA

Shaded areas contain advance information.

#### **Pin Definitions**

Pin Name	36-SOJ Pin Number	44 TSOP-II Pin Number	I/O Type	Description
A <sub>0</sub> -A <sub>18</sub>	1–5,14–18, 20–24,32–35	3–7,16–20, 26–30,38–41	Input	Address Inputs used to select one of the address locations.
I/O <sub>0</sub> –I/O <sub>7</sub>	7,8,11,12,25, 26,29,30	9,10,13,14, 31,32,35,36	Input/Output	<b>Bidirectional Data I/O lines.</b> Used as input or output lines depending on operation
NC <sup>[2]</sup>	19,36	1,2,21,22,23, 24,25,42,43, 44	No Connect	No Connects. This pin is not connected to the die
WE	13	15	Input/Control	<b>Write Enable Input, active LOW.</b> When selected LOW, a WRITE is conducted. When selected HIGH, a READ is conducted.
CE	6	8	Input/Control	Chip Enable Input, active LOW. When LOW, selects the chip. When HIGH, deselects the chip.
ŌĒ	31	37	Input/Control	Output Enable, active LOW. Controls the direction of the I/O pins. When LOW, the I/O pins are allowed to behave as outputs. When deasserted HIGH, I/O pins are three-stated, and act as input data pins.
V <sub>SS</sub> , GND	10,28	12,34	Ground	<b>Ground for the device.</b> Should be connected to ground of the system.
V <sub>CC</sub>	9,27	11,33	Power Supply	Power Supply inputs to the device.

Notes:
2. NC pins are not connected on the die.



## **Maximum Ratings**

(Above which the useful life may be impaired. For user guidelines, not tested.) Storage Temperature ......-65°C to +150°C Ambient Temperature with

Power Applied.....-55°C to +125°C Supply Voltage on V<sub>CC</sub> to Relative GND<sup>[3]</sup>–0.5V to +4.6VDC

Voltage Applied to Outputs in High-Z State  $^{[3]}$  ......-0.5V to  $\rm V_{CC}$  + 0.5V

## **Electrical Characteristics** Over the Operating Range

Input Voltage <sup>[3]</sup>	0.5V to V <sub>CC</sub> + 0.5V
Current into Outputs (LOW)	20 mA

## **Operating Range**

Range	Ambient Temperature	V <sub>CC</sub>
Commercial	0°C to +70°C	$3.3\text{V} \pm 0.3\text{V}$
Industrial	-40°C to +85°C	
Automotive	-40°C to +125°C	

				-	·8	-10 -12		12		
Parameter	Description	Test Condition	ns	Min.	Max.	Min.	Max.	Min.	Max.	Unit
V <sub>OH</sub>	Output HIGH Voltage	$V_{CC} = Min.; I_{OH} = -4.0 \text{ m}$	nΑ	2.4		2.4		2.4		V
V <sub>OL</sub>	Output LOW Voltage	V <sub>CC</sub> = Min.,; I <sub>OL</sub> = 8.0 m.	A		0.4		0.4		0.4	V
V <sub>IH</sub>	Input HIGH Voltage			2.0	V <sub>CC</sub> + 0.3	2.0	V <sub>CC</sub> + 0.3	2.0	V <sub>CC</sub> + 0.3	V
V <sub>IL</sub>	Input LOW Voltage[3]			-0.3	0.8	-0.3	0.8	-0.3	0.8	V
I <sub>IX</sub>	Input Load Current	$GND \le V_I \le V_{CC}$	Com'l/Ind'l	-1	+1	-1	+1	-1	+1	μА
I <sub>OZ</sub>	Output Leakage Current	GND ≤ V <sub>OUT</sub> ≤ V <sub>CC</sub> , Output Disabled	Com'l/Ind'l	-1	+1	-1	+1	-1	+1	μА
I <sub>CC</sub>	V <sub>CC</sub> Operating	V <sub>CC</sub> = Max.,	Com'l		100		90		85	mA
	Supply Current	$f = f_{MAX} = 1/t_{RC}$	Ind'l		110		100		95	mA
I <sub>SB1</sub>	Automatic CE Power-down Current —TTL Inputs	$\begin{aligned} &\text{Max. V}_{CC},  \overline{CE} \geq V_{IH}; \\ &V_{IN} \geq V_{IH} \text{ or } \\ &V_{IN} \leq V_{IL},  f = f_{MAX} \end{aligned}$	Com'l/Ind'l		40		40		40	mA
I <sub>SB2</sub>	Automatic CE Power-down Current —CMOS Inputs	$\begin{split} & \underline{\text{Max}}. \ V_{\text{CC}}, \\ & \text{CE} \geq V_{\text{CC}} - 0.3 \text{V}, \\ & V_{\text{IN}} \geq V_{\text{CC}} - 0.3 \text{V}, \\ & \text{or} \ V_{\text{IN}} \leq 0.3 \text{V}, \ \text{f} = 0 \end{split}$	Com'l/Ind'l		10		10		10	mA

#### **Electrical Characteristics** Over the Operating Range

			Test Conditions N		-15		-20	
Parameter	Description	Test Condi			Max.	Min.	Max.	Unit
V <sub>OH</sub>	Output HIGH Voltage	$V_{CC} = Min.; I_{OH} = -4.0 r$	nA	2.4		2.4		V
$V_{OL}$	Output LOW Voltage	$V_{CC} = Min.,; I_{OL} = 8.0 \text{ m}$	V <sub>CC</sub> = Min.,; I <sub>OL</sub> = 8.0 mA		0.4		0.4	V
V <sub>IH</sub>	Input HIGH Voltage				$V_{CC} + 0.3$	2.0	$V_{CC} + 0.3$	V
V <sub>IL</sub>	Input LOW Voltage[3]			-0.3	0.8	-0.3	0.8	V
I <sub>IX</sub>	Input Load Current	$GND \le V_I \le V_{CC}$	Com'l / Ind'l	-1	+1	-1	+1	μА
			Automotive	-20	+20	-	-	μА
I <sub>OZ</sub>	Output Leakage	$GND \leq V_{OUT} \leq V_{CC},$	Com'l / Ind'l	-1	+1	-1	+1	μА
	Current	Output Disabled	Automotive	-20	+20	-	-	μА
I <sub>CC</sub>	V <sub>CC</sub> Operating	V <sub>CC</sub> = Max.,	Com'l		80		80	mΑ
	Supply Current	$f = f_{MAX} = 1/t_{RC}$	Ind'I		90		90	mΑ
			Automotive		95		-	mΑ

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<sup>3.</sup>  $V_{IL}$  (min.) = -2.0V and  $V_{IH}$ (max) =  $V_{CC}$  + 0.5V for pulse durations of less than 20 ns.



#### **Electrical Characteristics** Over the Operating Range (continued)

				-15		-20		
Parameter	Description	Description Test Conditions			Max.	Min.	Max.	Unit
I <sub>SB1</sub>	Automatic CE	Max. $V_{CC}$ , $\overline{CE} \ge V_{IH}$ ;	Com'l / Ind'l		40		40	mA
Power-down Current V <sub>I</sub> —TTL Inputs V <sub>I</sub>	$V_{IN} \ge V_{IH}$ or $V_{IN} \le V_{IL}$ , $f = f_{MAX}$	Automotive		45		-	mA	
I <sub>SB2</sub>	SB2 Automatic CE Max. V <sub>CC</sub> ,	Max. V <sub>CC</sub> ,	Com'l/Ind'l		10		10	mA
	Power-down Current —CMOS Inputs	$CE \ge V_{CC} - 0.3V$ , $V_{IN} \ge V_{CC} - 0.3V$ , or $V_{IN} \le 0.3V$ , $f = 0$	Automotive		15		-	mA

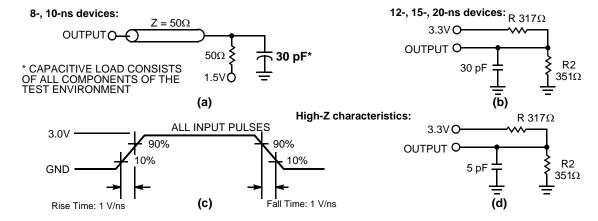
#### Thermal Resistance<sup>[4]</sup>

Parameter	Description	Test Conditions	36-pin SOJ (Non Pb-Free)	36-pin SOJ (Pb-Free)		44-TSOP-II (Pb-Free)	Unit
$\Theta_{JA}$	Thermal Resistance (Junction to Ambient)	Test conditions follow standard test methods	46.51	46.51	41.66	41.66	°C/W
$\Theta_{JC}$	Thermal Resistance (Junction to Case)	and procedures for measuring thermal impedance, per EIA / JESD51.	18.8	18.8	10.56	10.56	°C/W

### Capacitance<sup>[4]</sup>

Parameter	Description	Test Conditions	Max.	Unit
C <sub>IN</sub>	Input Capacitance	$T_A = 25^{\circ}C, f = 1 \text{ MHz},$	8	pF
C <sub>OUT</sub>	I/O Capacitance	$V_{CC} = 3.3V$	8	pF

#### AC Test Loads and Waveforms<sup>[5]</sup>



#### Notes:

- 4. Tested initially and after any design or process changes that may affect these parameters.
- 5. AC characteristics (except High-Z) for all 8-ns and 10-ns parts are tested using the load conditions shown in Figure (a). All other speeds are tested using the Thevenin load shown in Figure (b). High-Z characteristics are tested for all speeds using the test load shown in Figure (d).

[+] Feedback



### AC Switching Characteristics Over the Operating Range [6]

			-8		-10		-12	
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Unit
Read Cycle		•	•	•			•	1
t <sub>power</sub> <sup>[7]</sup>	V <sub>CC</sub> (typical) to the first access	1		1		1		μS
t <sub>RC</sub>	Read Cycle Time	8		10		12		ns
t <sub>AA</sub>	Address to Data Valid		8		10		12	ns
t <sub>OHA</sub>	Data Hold from Address Change	3		3		3		ns
t <sub>ACE</sub>	CE LOW to Data Valid		8		10		12	ns
t <sub>DOE</sub>	OE LOW to Data Valid		4		5		6	ns
t <sub>LZOE</sub>	OE LOW to Low-Z	0		0		0		ns
t <sub>HZOE</sub>	OE HIGH to High-Z <sup>[8, 9]</sup>		4		5		6	ns
t <sub>LZCE</sub>	CE LOW to Low-Z <sup>[9]</sup>	3		3		3		ns
t <sub>HZCE</sub>	CE HIGH to High-Z <sup>[8, 9]</sup>		4		5		6	ns
t <sub>PU</sub>	CE LOW to Power-up	0		0		0		ns
t <sub>PD</sub>	CE HIGH to Power-down		8		10		12	ns
Write Cycle <sup>[</sup>	10, 11]							
t <sub>WC</sub>	Write Cycle Time	8		10		12		ns
t <sub>SCE</sub>	CE LOW to Write End	6		7		8		ns
t <sub>AW</sub>	Address Set-up to Write End	6		7		8		ns
t <sub>HA</sub>	Address Hold from Write End	0		0		0		ns
t <sub>SA</sub>	Address Set-up to Write Start	0		0		0		ns
t <sub>PWE</sub>	WE Pulse Width	6		7		8		ns
t <sub>SD</sub>	Data Set-up to Write End	4		5		6		ns
t <sub>HD</sub>	Data Hold from Write End	0		0		0		ns
t <sub>LZWE</sub>	WE HIGH to Low-Z <sup>[9]</sup>	3		3		3		ns
t <sub>HZWE</sub>	WE LOW to High-Z <sup>[8, 9]</sup>		4		5		6	ns

Shaded areas contain advance information.

## AC Switching Characteristics Over the Operating Range [6]

			-15 -20		20				
Parameter	Description	Min.	Max.	Min.	Max.	Unit			
Read Cycle	•								
t <sub>power</sub> <sup>[7]</sup>	V <sub>CC</sub> (typical) to the first access	1		1		μS			
t <sub>RC</sub>	Read Cycle Time	15		20		ns			
t <sub>AA</sub>	Address to Data Valid		15		20	ns			
t <sub>OHA</sub>	Data Hold from Address Change		3		3	ns			
t <sub>ACE</sub>	CE LOW to Data Valid		15		20	ns			
t <sub>DOE</sub>	OE LOW to Data Valid		7		8	ns			

- 6. Test conditions assume signal transition time of 3 ns or less, timing reference levels of 1.5V, input pulse levels of 0 to 3.0V.

- Test conditions assume signal transition time of 3 ns or less, timing reference levels of 1.5V, input pulse levels of 0 to 3.0V.
   t<sub>POWER</sub> gives the minimum amount of time that the power supply should be at stable, typical V<sub>CC</sub> values until the first memory access can be performed.
   t<sub>HZOE</sub>, t<sub>HZOE</sub>, t<sub>HZOE</sub>, and t<sub>HZWE</sub> are specified with a load capacitance of 5 pF as in part (d) of AC Test Loads. Transition is measured ±500 mV from steady-state voltage.
   At any given temperature and voltage condition, t<sub>HZCE</sub> is less than t<sub>LZOE</sub>, t<sub>HZOE</sub> is less than t<sub>LZOE</sub>, and t<sub>HZWE</sub> is less than t<sub>LZWE</sub> for any given device.
   The internal Write time of the memory is defined by the overlap of CE LOW, and WE LOW. CE and WE must be LOW to initiate a Write, and the transition of either of these signals can terminate the Write. The input data set-up and hold timing should be referenced to the leading edge of the signal that terminates the Write.
   The minimum Write cycle time for Write Cycle No. 3 (WE controlled, OE LOW) is the sum of t<sub>HZWE</sub> and t<sub>SD</sub>.

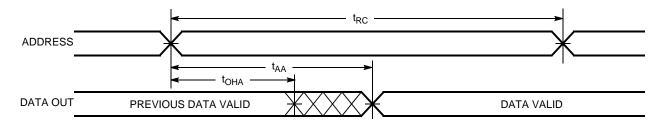


## AC Switching Characteristics Over the Operating Range (continued)<sup>[6]</sup>

		-	15	-		
Parameter	Description	Min.	Max.	Min.	Max.	Unit
t <sub>LZOE</sub>	OE LOW to Low-Z	0		0		ns
t <sub>HZOE</sub>	OE HIGH to High-Z <sup>[8, 9]</sup>		7		8	ns
t <sub>LZCE</sub>	CE LOW to Low-Z <sup>[9]</sup>	3		3		ns
t <sub>HZCE</sub>	CE HIGH to High-Z <sup>[8, 9]</sup>		7		8	ns
t <sub>PU</sub>	CE LOW to Power-up	0		0		ns
t <sub>PD</sub>	CE HIGH to Power-down		15		20	ns
Write Cycle <sup>[</sup>	0, 11]		1	•	•	•
t <sub>WC</sub>	Write Cycle Time	15		20		ns
t <sub>SCE</sub>	CE LOW to Write End	10		10		ns
t <sub>AW</sub>	Address Set-up to Write End	10		10		ns
t <sub>HA</sub>	Address Hold from Write End	0		0		ns
t <sub>SA</sub>	Address Set-up to Write Start	0		0		ns
t <sub>PWE</sub>	WE Pulse Width	10		10		ns
t <sub>SD</sub>	Data Set-up to Write End	7		8		ns
t <sub>HD</sub>	Data Hold from Write End	0		0		ns
t <sub>LZWE</sub>	WE HIGH to Low-Z <sup>[9]</sup>	3		3		ns
t <sub>HZWE</sub>	WE LOW to High-Z <sup>[8, 9]</sup>		7		8	ns

## **Switching Waveforms**

Read Cycle No. 1<sup>[12, 13]</sup>

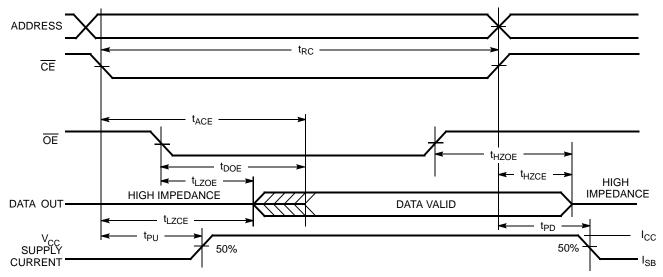


Notes: 12. Device is continuously selected.  $\overline{OE}$ ,  $\overline{CE} = V_{\parallel L}$ . 13. WE is HIGH for Read cycle.

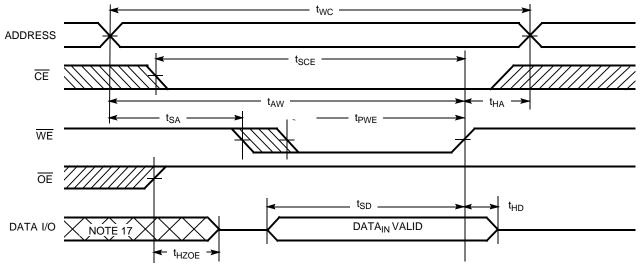


## Switching Waveforms (continued)

## Read Cycle No. 2 (OE Controlled)[13, 14]



## Write Cycle No. 1(WE Controlled, OE HIGH During Write)[15, 16]



- 14. Address valid prior to or coincident with  $\overline{\text{CE}}$  transition LOW.

  15. Data I/O is high-impedance if  $\overline{\text{OE}} = \text{V}_{\text{IH}}$ .

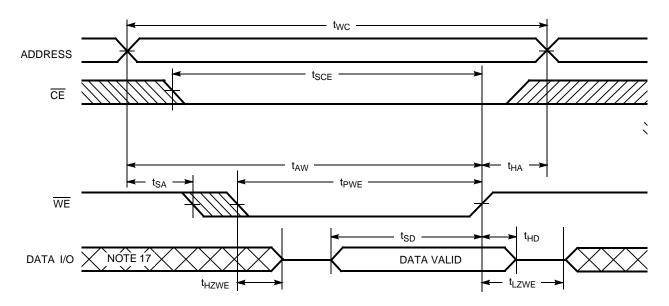
  16. If CE goes HIGH simultaneously with WE going HIGH, the output remains in a high-impedance state.

  17. During this period the I/Os are in the output state and input signals should not be applied.



## Switching Waveforms (continued)

Write Cycle No. 2 ( $\overline{\text{WE}}$  Controlled,  $\overline{\text{OE}}$  LOW)[16]





### **Truth Table**

CE	OE	WE	I/O <sub>0</sub> -I/O <sub>7</sub>	Mode	Power
Н	Х	X	High-Z	Power-down	Standby (I <sub>SB</sub> )
L	L	Н	Data Out	Read	Active (I <sub>CC</sub> )
L	Х	L	Data In	Write	Active (I <sub>CC</sub> )
L	Н	Н	High-Z	Selected, Outputs Disabled	Active (I <sub>CC</sub> )

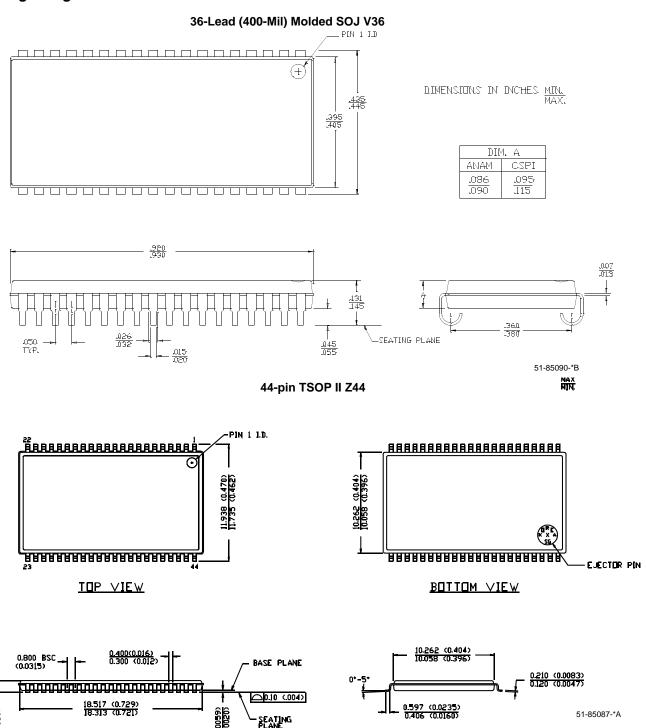
## **Ordering Information**

Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
10	CY7C1049CV33-10VC	V36	36-lead (400-Mil) Molded SOJ	Commercial
	CY7C1049CV33-10ZC	Z44	44-pin TSOP II	
	CY7C1049CV33-10VI	V36	36-lead (400-Mil) Molded SOJ	Industrial
	CY7C1049CV33-10ZI	Z44	44-pin TSOP II	
12	CY7C1049CV33-12VC	V36	36-lead (400-Mil) Molded SOJ	Commercial
	CY7C1049CV33-12ZC	Z44	44-pin TSOP II	
	CY7C1049CV33-12VI	V36	36-lead (400-Mil) Molded SOJ	Industrial
	CY7C1049CV33-12ZI	Z44	44-pin TSOP II	
15	CY7C1049CV33-15VC	V36	36-lead (400-Mil) Molded SOJ	Commercial
	CY7C1049CV33-15ZC	Z44	44-pin TSOP II	
	CY7C1049CV33-15VI	V36	36-lead (400-Mil) Molded SOJ	Industrial
	CY7C1049CV33-15ZI	Z44	44-pin TSOP II	
	CY7C1049CV33-15VE	V36	36-lead (400-Mil) Molded SOJ	Automotive
	CY7C1049CV33-15ZSE	Z44	44-pin TSOP II	
20	CY7C1049CV33-20VC	V36	36-lead (400-Mil) Molded SOJ	Commercial
	CY7C1049CV33-20VI	V36	36-lead (400-Mil) Molded SOJ	Industrial
10	CY7C1049CV33-10VXC	V36	36-lead (400-Mil) Molded SOJ (Pb-Free)	Commercial
	CY7C1049CV33-10ZXC	Z44	44-pin TSOP II (Pb-Free)	
	CY7C1049CV33-10VXI	V36	36-lead (400-Mil) Molded SOJ (Pb-Free)	Industrial
	CY7C1049CV33-10ZXI	Z44	44-pin TSOP II (Pb-Free)	Industrial
12	CY7C1049CV33-12VXC	V36	36-lead (400-Mil) Molded SOJ (Pb-Free)	Commercial
	CY7C1049CV33-12ZXC	Z44	44-pin TSOP II (Pb-Free)	
	CY7C1049CV33-12VXI	V36	36-lead (400-Mil) Molded SOJ (Pb-Free)	Industrial
	CY7C1049CV33-12ZXI	Z44	44-pin TSOP II (Pb-Free)	
15	CY7C1049CV33-15VXC	V36	36-lead (400-Mil) Molded SOJ (Pb-Free)	Commercial
	CY7C1049CV33-15ZXC	Z44	44-pin TSOP II (Pb-Free)	
	CY7C1049CV33-15VXI	V36	36-lead (400-Mil) Molded SOJ (Pb-Free)	Industrial
	CY7C1049CV33-15ZXI	Z44	44-pin TSOP II (Pb-Free)	
	CY7C1049CV33-15VXE	V36	36-lead (400-Mil) Molded SOJ (Pb-Free)	Automotive
	CY7C1049CV33-15ZSXE	Z44	44-pin TSOP II	Automotive
20	CY7C1049CV33-20VXC	V36	36-lead (400-Mil) Molded SOJ (Pb-Free)	Commercial
	CY7C1049CV33-20VXI	V36	36-lead (400-Mil) Molded SOJ (Pb-Free)	Industrial

Shaded areas contain advance information. Please contact your local Cypress Sales representative for availability of these parts.



### **Package Diagrams**



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## **Document History Page**

Document Title: CY7C1049CV33 4-Mbit (512K x 8) Static RAM Document Number: 38-05006							
REV.	ECN NO.	Issue Date	Orig. of Change	Description of Change			
**	112569	03/06/02	HGK	New data sheet			
*A	114091	04/25/02	DFP	Changed Tpower unit from ns to μs			
*B	116479	09/16/02	CEA	Add applications foot note to data sheet, page 1.			
*C	262949	See ECN	RKF	Added Automotive Specs Added $\Theta_{\rm JA}$ and $\Theta_{\rm JC}$ values on Page #3.			
*D	300091	See ECN	RKF	Added -20-ns Speed bin			
*E	344595	See ECN	SYT	Added Pb-Free package on page #8 Removed shading for CY7C1049CV33-15ZSXE in the ordering Information on page 9			